Re-Inventing Delta Modulation

Back in the late 70s and early 80s, it was believed at National Semiconductor, that it was impossible to build a Analog to digital convertor with greater than 12bits.

The argument was that the temperature coefficient of the matching elements was not low enough.

The following idea was presented to Rod Russell, who was the design manager for ADCs and DACs at that time. The argument was, if you did this, why can't you build a 20bit ADC?

How to build an ADC using a Counter, a Comparator, and a R and C. ^+10V * .D FF..... 20MHz sample * VIN INP1 ٧n S1 Up/Dwn DOUT INN1 Counter 1Vppk * -C2 : -10v\ +10V= Up : -10V = DwnVsiq * Out1 7/7 * **R1** 3KHz 1nF 300k 530Hz **C1** 100dB loop gain

At the time, Opamps were designed for +/-15V supplies. Take the fastest voltage comparator with a latching output. Such a comparator always has a large referred to input noise, since its bandwidth is as high as possible.

It should be possible to find a set of Resistor/Capacitor feedback values where the comparator is stable in negative feedback.

Now if the input signal is a slow sine wave, the voltage across the capacitor will track it. Since the resistor/capacitor is being driven by a latched digital signal, how is the value of the voltage across the capacitor operating any different from that of an Up/Down counter which is connected to the same latched digital output node?

As it turns out, this Delta Modulation method was invented in 1946. And at that very same time, Analog engineers were rediscovering it. But nobody at National Semiconductor had seen this concept it before. It was not long afterwards that Sigma-Delta ADCs became mainstream.



The plots of the two inputs to the comparator are shown above. The negative input voltage has an offset of 100mV to show both inputs. A 5Mhz random PWL noise voltage has been put in series with the input signal to simulate the input noise of the comparator.







The output of the comparator is being latched at a 20MHz rate. This simulation is using a simple sample and hold.



The spectrum of the capacitor voltage will have a slightly lower bandwidth. At lower frequencies, the capacitor will track the input signal, noise and all.



The voltage across the capacitor shows what the a UP/Down counter running off the same latch digital output should be seeing.

There appears to be less noise in the capacitor, since the comparator was not simulated with infinite gain bandwidth. But for frequencies below 100kHz, the spectrums are effectively the same.

Now to create high bandwidth comparators, input stages need to run a lot of supply current. Higher input currents lower impedances and input noise voltages. While the comparator's bandwidth will make the referred to input noise large, it is only it's noise at the lower frequencies that count.



```
*plot
           inpl outl innl out0
plot
          outl innl
           out0 out1/1.1 5*cntl xlimit .5m .502m
plot
echo
           linearize
          FFT_BandWidth_Hz =
FFT_resolution_Hz =
"FFT_BandWidth_Hz=
                          10Meg
let
let
                          1k
                          $&FFT_BandWidth_Hz"
echo
           "FFT_resolution_Hz=
                          $&FFT_resolution_Hz"
echo
mag (inn1) loglog
plot
```

```
destroy
```

destroy

echo	"=====================================	
linearize		
let	FFT BandWidth Hz =	10Meg
let	FFT resolution Hz =	1k
echo	"FFT BandWidth Hz=	\$&FFT BandWidth Hz"
echo	"FFT resolution Hz=	\$&FFT resolution Hz"
set	specwindow=	"rectangular"
spec	\$&FFT resolution Hz	\$&FFT BandWidth Hz \$&FFT resolution Hz v(inpl)
let expect V =	(sqrt(2)/sqrt(500k/1k))/	(1+(frequency/550k)*(frequency/500k)*(frequency/500k)*(frequency/
500k) * (frequency)	/500k))	
plot	mag (inpl) loglog	
echo	"======done	"

.endc

.end

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